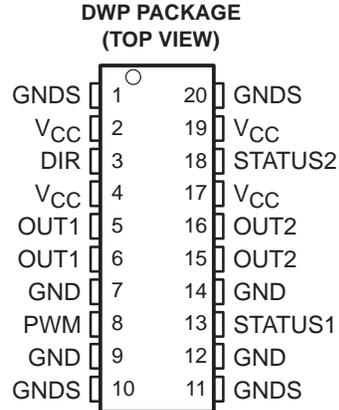


- Dedicated PWM Input Port
- Optimized for Reversible Operation of Motors
- Two Input Control Lines for Reduced Microcontroller Overhead
- Internal Current Shutdown of 5 A
- 40 V Load Dump Rating
- Integrated Fault Protection and Diagnostics
- CMOS Compatible Schmitt Trigger Inputs for High Noise Immunity



## description

The TPIC0107B is a PWM control intelligent H-bridge designed specifically for dc motor applications. The device provides forward, reverse, and brake modes of operation. A logic supply voltage of 5 V is internally derived from V<sub>CC</sub>.

The TPIC0107B has an extremely low r<sub>DS(on)</sub>, 280 mΩ typical, to minimize system power dissipation. The direction control (DIR) and PWM control (PWM) inputs greatly simplify the microcontroller overhead requirement. The PWM input can be driven from a dedicated PWM port while the DIR input is driven as a simple low speed toggle.

The TPIC0107B provides protection against over-voltage, over-current, over-temperature, and cross conduction faults. Fault diagnostics can be obtained by monitoring the STATUS1 and STATUS2 terminals and the two input control lines. STATUS1 is an open-drain output suitable for wired-or connection. STATUS2 is a push-pull output that provides a latched status output. Under-voltage protection ensures that the outputs, OUT1 and OUT2, will be disabled when V<sub>CC</sub> is less than the under-voltage detection voltage V<sub>(UVCC)</sub>.

The TPIC0107B is designed using TI's LinBiCMOS™ process. LinBiCMOS allows the integration of low power CMOS structures, precision bipolar cells, and low impedance DMOS transistors.

The TPIC0107B is offered in a 20-pin thermally enhanced small-outline package (DWP) and is characterized for operation over the operating case temperature of –40°C to 125°C.

FUNCTION TABLE

DIR	PWM	OUT1	OUT2	MODE
0	0	HS	HS	Brake, both HSDs turned on hard
0	1	HS	LS	Motor turns counter clockwise
1	0	HS	HS	Brake, both HSDs turned on hard
1	1	LS	HS	Motor turns clockwise



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



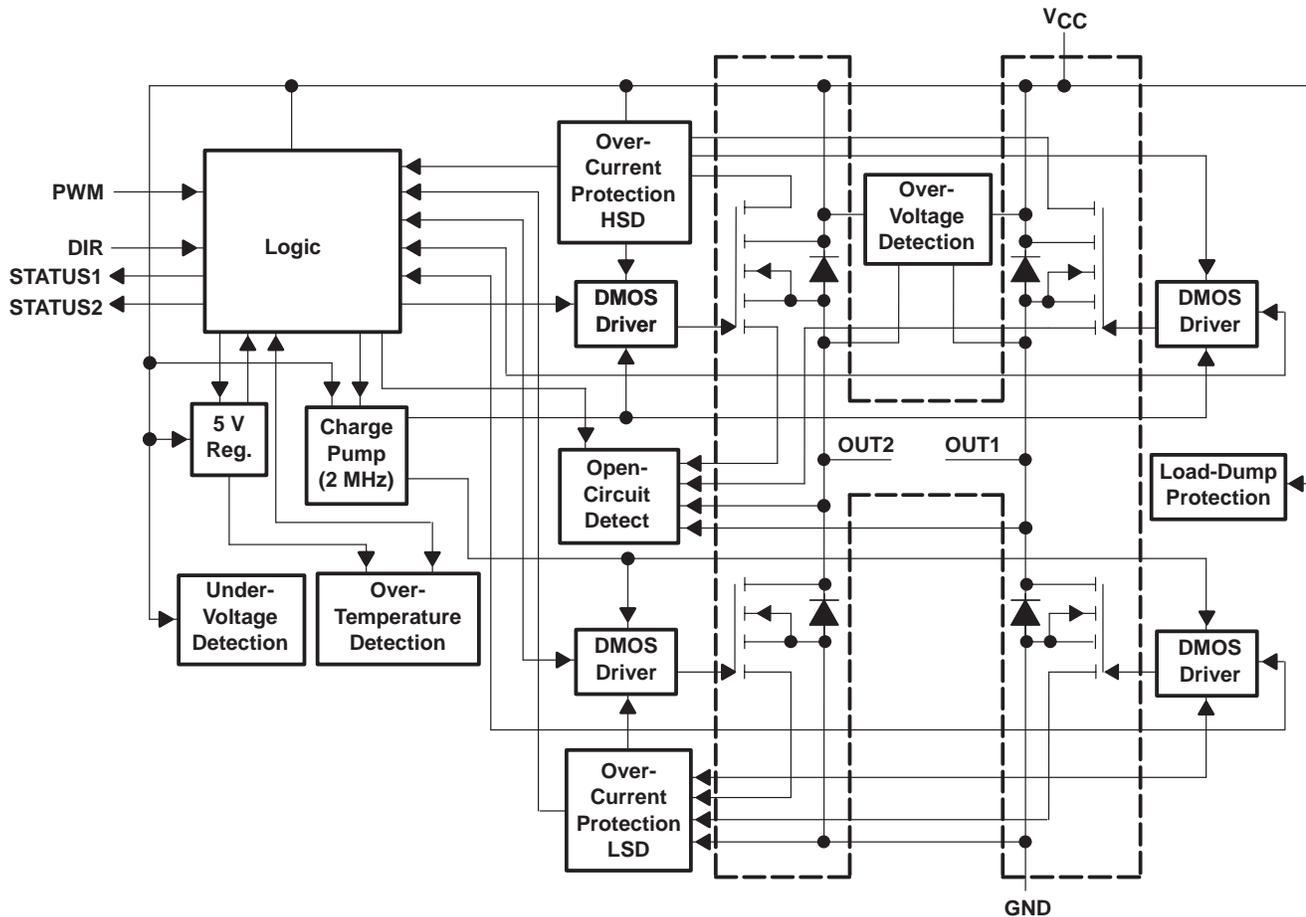
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# TPIC0107B PWM CONTROL INTELLIGENT H-BRIDGE

SLIS067 – NOVEMBER 1998

## block diagram



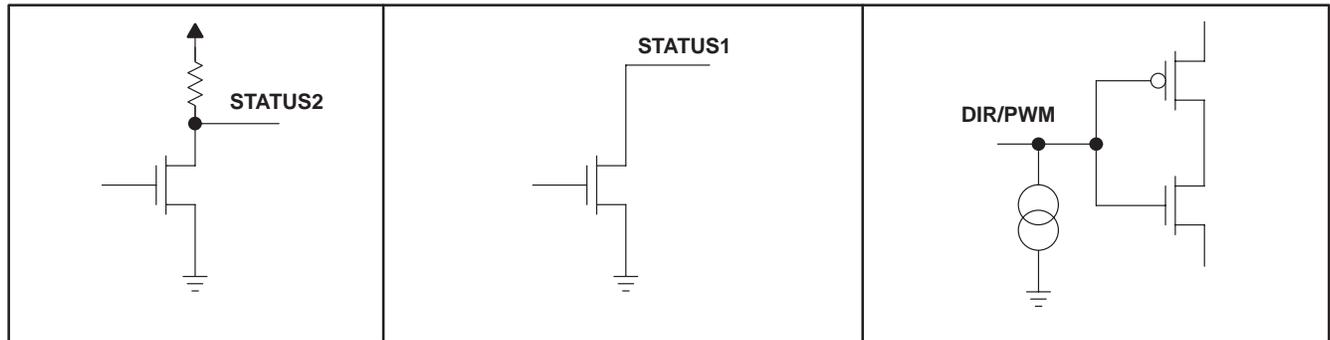
## Terminal Functions

TERMINAL NAME	NO.	I/O	DESCRIPTION
DIR	3	I	Direction control input
GND	7, 9, 12, 14	I	Power ground
GNDS	1, 10, 11, 20	I	Substrate ground
OUT1	5, 6	O	Half-H output. DMOS output
OUT2	15, 16	O	Half-H output. DMOS output
PWM	8	I	PWM control input
STATUS1	13	O	Status output
STATUS2	18	O	Latched status output
V <sub>CC</sub>	2, 4, 17, 19	I	Supply voltage

NOTE: It is mandatory that all four ground terminals plus at least one substrate terminal are connected to the system ground. Use all V<sub>CC</sub> and OUT terminals.



schematics of inputs and outputs



absolute maximum ratings over operating case temperature range (unless otherwise noted)†

Power supply voltage range, $V_{CC}$ .....	-0.3 V to 33 V
Logic input voltage range, $V_{IN}$ .....	-0.3 V to 7 V
Load dump (for 400 ms, $T_C = 25^\circ\text{C}$ ) .....	40 V
Status output voltage range, $V_{O(\text{status})}$ .....	-0.3 V to 7 V
Continuous power dissipation, $T_C = 25^\circ\text{C}$ .....	25 W
Storage temperature range, $T_{\text{stg}}$ .....	-55°C to 150°C
Maximum junction temperature, $T_J$ .....	150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

DISSIPATION RATING TABLE

$T_A \leq 25^\circ\text{C}$ POWER RATING	DERATING FACTOR ABOVE $T_A = 25^\circ\text{C}$	$T_A = 70^\circ\text{C}$ POWER RATING	$T_A = 125^\circ\text{C}$ POWER RATING
25 W	-0.2 W/°C	16 W	5 W

recommended operating conditions

	MIN	MAX	UNIT
Supply voltage, $V_{CC}$	6	18	V
Operating case temperature, $T_C$	-40	125	°C
Switching frequency, $f_{\text{PWM}}$		2	kHz

# TPIC0107B

## PWM CONTROL INTELLIGENT H-BRIDGE

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electrical characteristics over recommended operating case temperature range and  $V_{CC} = 5\text{ V}$  to  $6\text{ V}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$r_{DS(on)}$	Static drain-source on-resistance (per transistor) $I_{(BR)} = 1\text{ A}$	LSD	$T_J = 25^\circ\text{C}$		550	$\text{m}\Omega$
			$T_J = 150^\circ\text{C}$		850	
		HSD	$T_J = 25^\circ\text{C}$		600	$\text{m}\Omega$
			$T_J = 150^\circ\text{C}$		870	
$I_{(QCD)}$	Open circuit detection current		10	40	100	$\text{mA}$
$V_{(UVCC(OFF))}$	Under voltage detection on $V_{CC}$ , switch off voltage	See Note 1			5	$\text{V}$
$V_{(UVCC(ON))}$	Under voltage detection on $V_{CC}$ , switch on voltage	See Note 1			5.2	$\text{V}$
$V_{(STL)}$	STATUS low output voltage	$I_O = 100\ \mu\text{A}$ , See Note 1			0.8	$\text{V}$
$V_{(ST2H)}$	STATUS2 high output voltage	$I_O = 20\ \mu\text{A}$ , See Note 1	3		5.4	$\text{V}$
$I_{(ST(OFF))}$	STATUS output leakage current	$V_{(ST)} = 5\text{ V}$ , See Note 1			5	$\mu\text{A}$
$V_{IL}$	Low level logic input voltage		-0.3		0.5	$\text{V}$
$V_{IH}$	High level logic input voltage		3.6		7	$\text{V}$
$\Delta V_I$	Hysteresis of input voltage		0.3			$\text{V}$
$I_{IH}$	High level logic input current	$V_{IH} = 3.5\text{ V}$	2	10	50	$\mu\text{A}$

NOTE 1: The device functions according to the function table for  $V_{CC}$  between  $V_{(UVCC)}$  and  $5\text{ V}$  (no parameters specified). STATUS outputs are not defined for  $V_{CC}$  less than  $V_{(UVCC)}$ .



**electrical characteristics over recommended operating case temperature and supply voltage ranges (unless otherwise noted) (see Note 2)**

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
$r_{DS(on)}$	Static drain-source on-resistance (per transistor) $I_{BR} = 1$ A	$T_J = 25^\circ\text{C}$	$V_{CC} = 6$ V to 9 V		380	m $\Omega$	
			$V_{CC} = 9$ V to 18 V	280	340		
		$T_J = 150^\circ\text{C}$	$V_{CC} = 6$ V to 9 V		620		
			$V_{CC} = 9$ V to 18 V	400	560		
	HSD	$T_J = 25^\circ\text{C}$	$V_{CC} = 6$ V to 9 V		430		m $\Omega$
			$V_{CC} = 9$ V to 18 V	280	340		
		$T_J = 150^\circ\text{C}$	$V_{CC} = 6$ V to 9 V		640		
			$V_{CC} = 9$ V to 18 V	400	560		
$I_{(QCD)}$	Open circuit detection current		10	40	100	mA	
$T_{SDS}$	Static thermal shutdown temperature	See Notes 3 and 4	140			$^\circ\text{C}$	
$T_{SDD}$	Dynamic thermal shutdown temperature	See Notes 3 and 5	160			$^\circ\text{C}$	
$I_{CS}$	Current shutdown limit	$V_{CC} = 6$ V to 9 V	4.8		7.5	A	
		$V_{CC} = 9$ V to 18 V	5		7.5		
$I_{(CON)}$	Continuous bridge current	$T_J = 125^\circ\text{C}$ , Operating lifetime 10,000 hours, (see Figure 1)			3	A	
$V_{(OVCC)}$	Over voltage detection on $V_{CC}$		27		36	V	
$V_{(STL)}$	STATUS low output voltage	$I_O = 100$ $\mu\text{A}$			0.8	V	
$V_{(ST2H)}$	STATUS2 high output voltage	$I_O = 20$ $\mu\text{A}$	3.9		5.4	V	
$I_{(ST(OFF))}$	STATUS output leakage current	$V_{(ST)} = 5$ V			5	$\mu\text{A}$	
$V_{IL}$	Low level logic input voltage		-0.3		0.8	V	
$V_{IH}$	High level logic input voltage		3.6		7	V	
$\Delta V_I$	Hysteresis of input voltage		0.3			V	
$I_{IH}$	High level logic input current	$V_{IH} = 3.5$ V	2	10	50	$\mu\text{A}$	

- NOTES: 2. The device functions according to the function table for  $V_{CC}$  between 18 V and  $V_{(OVCC)}$ , but only up to a maximum supply voltage of 33 V (no parameters specified). Exposure beyond 18 V for extended periods may affect device reliability.  
3. Exposure beyond absolute-maximum-rated condition of junction temperature may affect device reliability.  
4. No temperature gradient between DMOS transistor and temperature sensor.  
5. With temperature gradient between DMOS transistor and temperature sensor in a typical application (DMOS transistor as heat source).

**switching characteristics over recommended operating case temperature and supply voltage ranges (unless otherwise noted)**

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{out(on)}$	High-side driver turn-on time	$V_{DS(on)} < 1$ V at 1 A, $V_{CC} = 13.2$ V			100	$\mu\text{s}$
	Low-side driver turn-on time				100	
SR	Slew rate, low-to-high sinusoidal ( $\delta V/\delta t$ )	$V_{CC} = 13.2$ V, $I_O = 1$ A resistive load	1		6	V/ $\mu\text{s}$
	Slew rate, high-to-low sinusoidal ( $\delta V/\delta t$ )		1		6	
$t_d(QCD)$	Under current spike duration to trigger open circuit detection	$V_{CC} = 5$ V to 18 V	1		10	ms
$t_d(CS)$	Delay time for over current shutdown		5	10	25	$\mu\text{s}$

**thermal resistance**

PARAMETER		MIN	MAX	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance		5	$^\circ\text{C}/\text{W}$
$R_{\theta JC}$	Junction-to-case thermal resistance		97	$^\circ\text{C}/\text{W}$



# TPIC0107B PWM CONTROL INTELLIGENT H-BRIDGE

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## PARAMETER MEASUREMENT INFORMATION

Maximum continuous bridge current versus time based on 50 FITs at 100,000 hours operating life (90% confidence model)

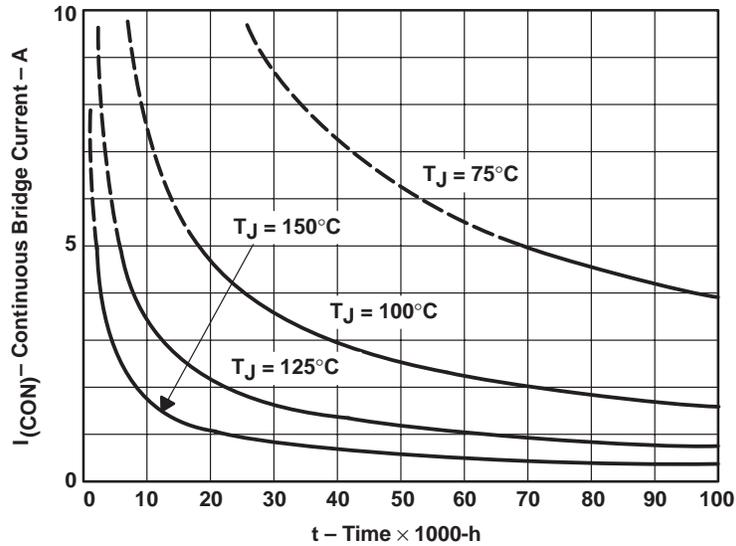


Figure 1. Electromigration Reliability Data

Example:

Average continuous bridge current, $I_{CON}$	Average junction temperature, $T_J$	Operating lifetime of device based on electromigration
2 A	125°C	>20,000 h
3 A	125°C	>10,000 h

PARAMETER MEASUREMENT INFORMATION

operating wave forms

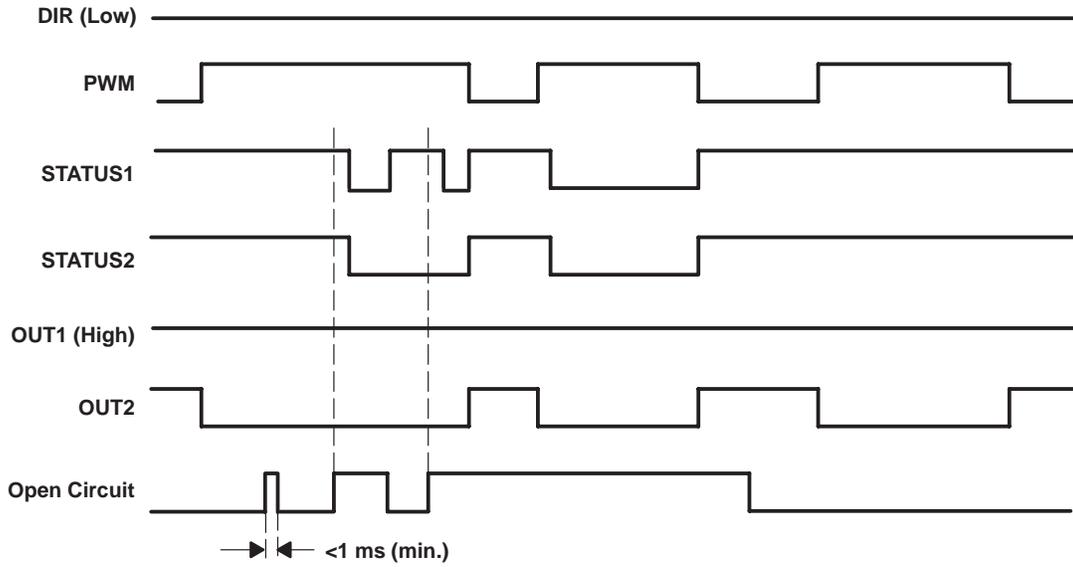


Figure 2. Open Circuit

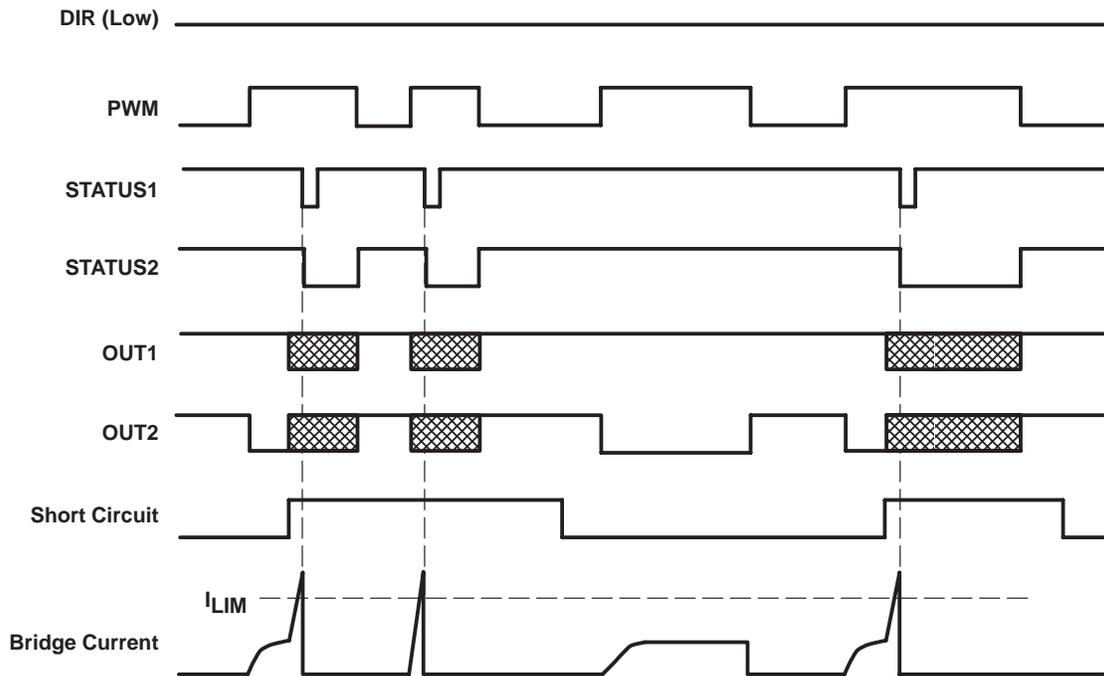


Figure 3. Short Circuit (e.g., OUT2 to  $V_{CC}$ )

PARAMETER MEASUREMENT INFORMATION

operating wave forms (continued)

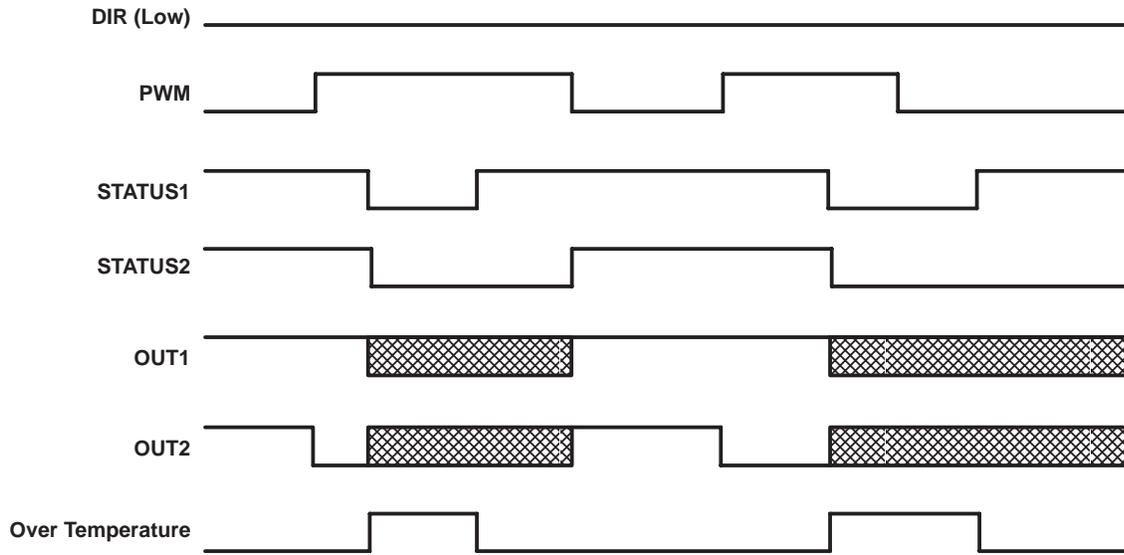


Figure 4. Over Temperature

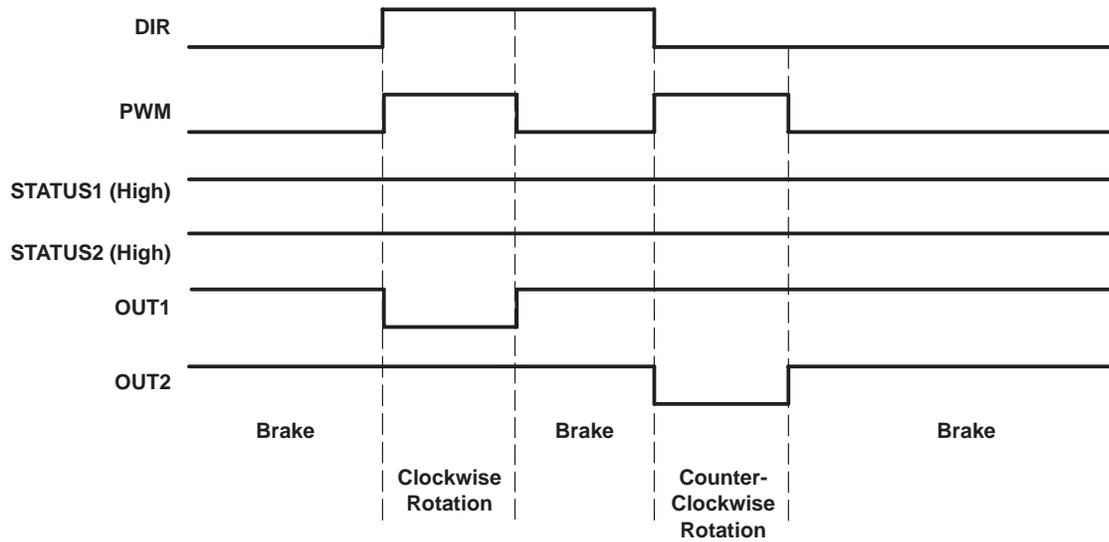


Figure 5. No Fault

## PRINCIPLES OF OPERATION

### protective functions and diagnostics†

#### over current/short circuit‡

The TPIC0107B detects shorts to  $V_{CC}$ , ground, or across the load being driven, by comparing the  $V_{DS}$  voltage drop across the DMOS outputs against the threshold voltage. The DMOS outputs of the TPIC0107B will be disabled and the fault flags will be generated 10  $\mu$ s after an over-current or short-circuit fault is detected. This 10  $\mu$ s delay is long enough to serve as a de-glitch filter for high current transients, yet short enough to prevent damage to the DMOS outputs. The DMOS outputs remain latched off until either DIR or PWM input is toggled.

In cases where the outputs have a continuous short-to-ground with a current rise time faster than 0.5 A/ $\mu$ s, the over-current shutdown threshold will decrease to 3 A to reduce power dissipation. This reduction to 3 A is achieved since the DMOS outputs will not be fully enhanced when the over-current threshold is reached if the current rise time exceeds 0.5 A/ $\mu$ s. Over-current and/or short-circuit protection is provided up to  $V_{CC} = 16.5$  V and a junction temperature of 90°C.

#### over temperature

The TPIC0107B disables all DMOS outputs and the fault flags will be set when  $T_J \geq 140^\circ\text{C}$  (min.). The DMOS outputs remain latched off until either DIR or PWM input is toggled.

#### under voltage

The TPIC0107B disables all DMOS outputs when  $V_{CC} \leq V_{(UVCC)}$ . The outputs will be re-enabled when  $V_{CC} \geq V_{(UVCC)}$ . No fault flags are set when under-voltage lockout occurs.

#### over voltage

In order to protect the DMOS outputs from damage caused by excessive supply voltage, the TPIC0107B disables all outputs when  $V_{CC} \geq V_{(OVCC)}$ . Once  $V_{CC} \leq V_{(OVCC)}$ , either DIR or PWM input must be toggled to re-enable the DMOS outputs.

#### cross conduction

Monitoring circuitry for each transistor detects whether the particular transistor is active to prevent the HSD or LSD of the corresponding half H-bridge from conducting.

#### open circuit

During operation, the bridge current is controlled continuously. If the bridge current is >10 mA (min.) for a period >1 ms (min.), the fault flags are set. However, the output transistors will not be disabled.

† All limits mentioned are typical values unless otherwise noted.

‡ If a short circuit occurs (i.e., the over-current detection circuitry is activated) at a supply voltage higher than 16.5 V and a junction temperature higher than 90°C, damage to the device may occur.

# TPIC0107B

## PWM CONTROL INTELLIGENT H-BRIDGE

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### PRINCIPLES OF OPERATION

DIAGNOSTICS TABLE (see Note 6)

FLAG	DIR	PWM	OUT1	OUT2	STATUS1†	STATUS2
Normal operation	0	0	HS	HS	1	1
	0	1	HS	LS	1	1
	1	0	HS	HS	1	1
	1	1	LS	HS	1	1
Open circuit between OUT1 and OUT2	0	0	HS	HS	1	1
	0	1	HS	LS	0	0
	1	0	HS	HS	1	1
	1	1	LS	HS	0	0
Short circuit from OUT1 to OUT2 (see Notes 7 and 8)	0	1	X	X	0	0
	1	1	X	X	0	0
Short circuit from OUT1 to GND (see Notes 7 and 8)	0	0	X	X	0	0
	1	0	X	X	0	0
	0	1	X	X	0	0
Short circuit from OUT2 to GND (see Notes 7 and 8)	0	0	X	X	0	0
	1	0	X	X	0	0
	1	1	X	X	0	0
Short circuit from OUT1 to V <sub>CC</sub> (see Notes 7 and 8)	1	1	X	X	0	0
Short circuit from OUT2 to V <sub>CC</sub> (see Notes 7 and 8)	0	1	X	X	0	0
Over temperature	0	0	Z	Z	0	0
	0	1	Z	Z	0	0
	1	0	Z	Z	0	0
	1	1	Z	Z	0	0

† When wired with a pull-up resistor

SYMBOL	VALUE
0	Logic low
1	Logic high
HS	High-side MOSFET conducting
LS	Low-side MOSFET conducting
Z	No output transistors conducting
X	Voltage level undefined

- NOTES: 6. All input combinations not stated result in STATUS output = 1.  
 7. STATUS1 active for a minimum of 3 μs.  
 8. STATUS2 active until an input is toggled.



TYPICAL CHARACTERISTICS

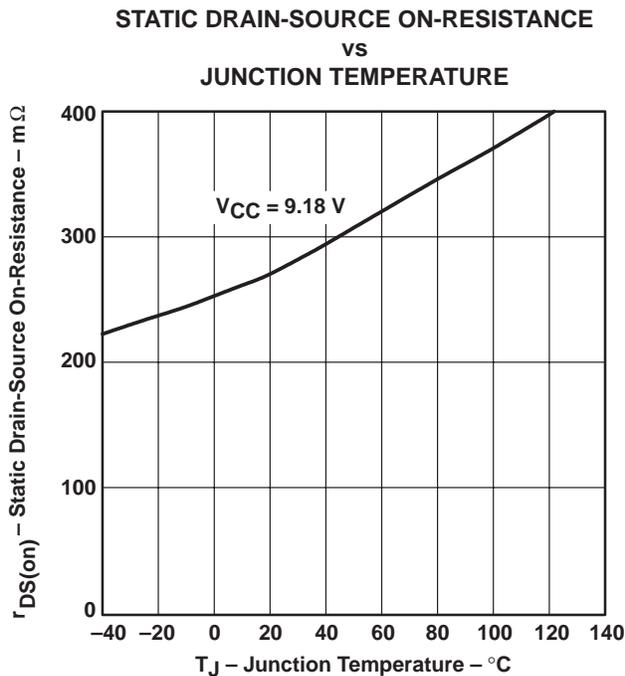


Figure 6

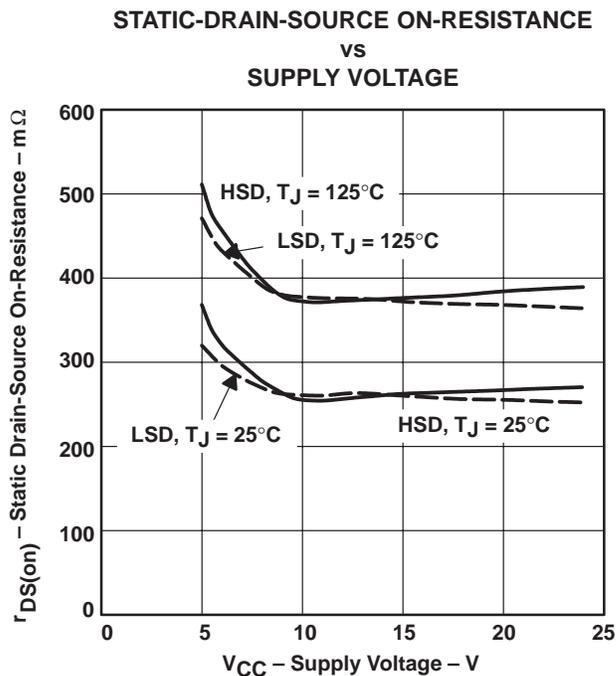


Figure 7

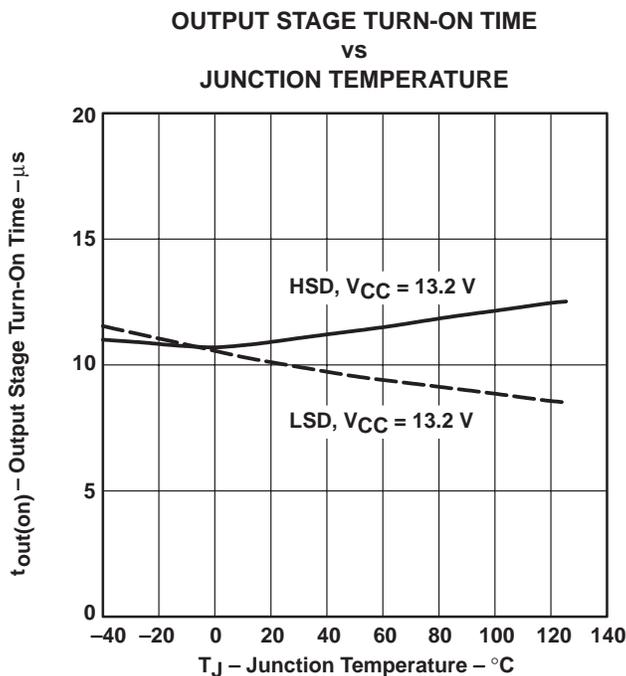
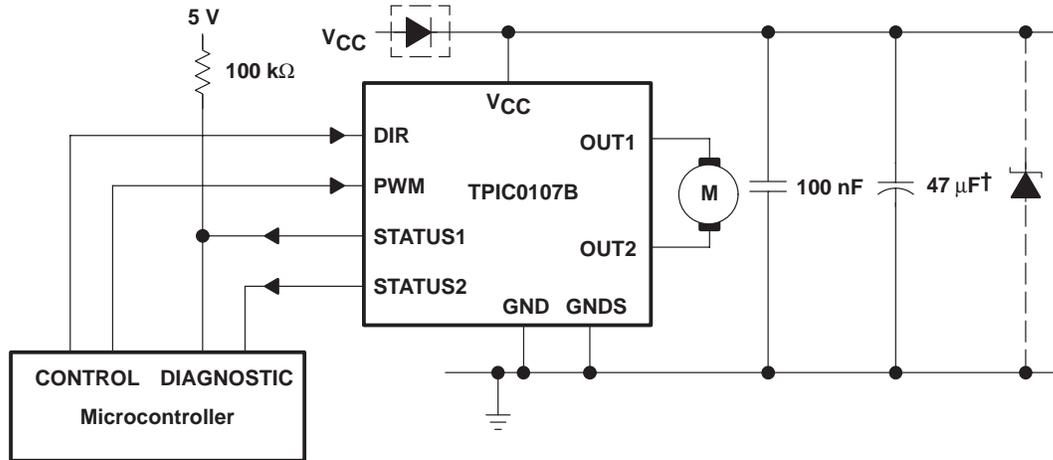


Figure 8

# TPIC0107B PWM CONTROL INTELLIGENT H-BRIDGE

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## APPLICATION INFORMATION



† Necessary for isolating supply voltage or interruption (e.g., 47 μF).

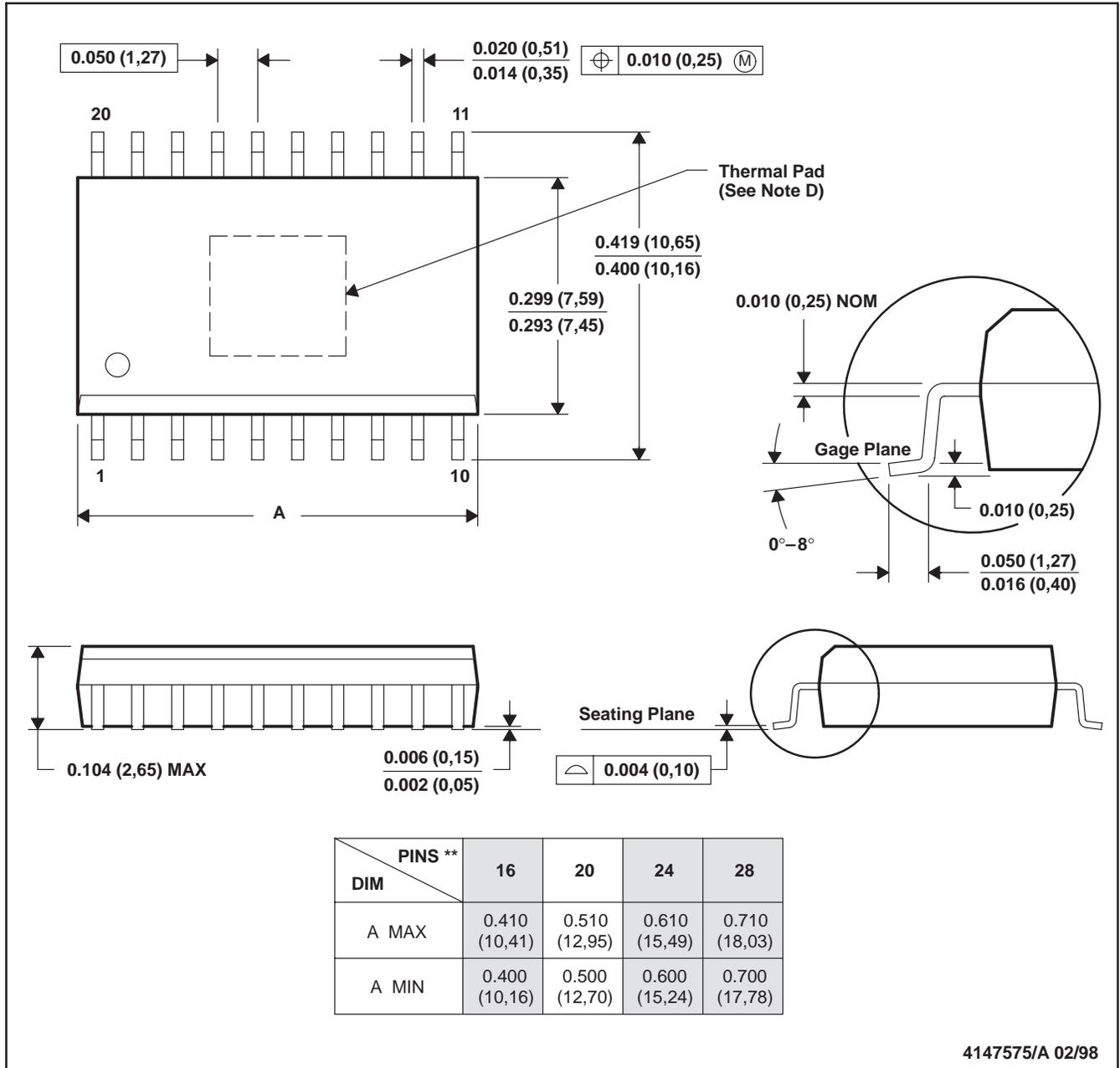
NOTE: If a STATUS output is not connected to the appropriate microcontroller input, it shall remain unconnected.

MECHANICAL DATA

DWP (R-PDSO-G\*\*)

PowerPAD™ PLASTIC SMALL-OUTLINE PACKAGE

20-PIN SHOWN



- NOTES: A. All linear dimensions are in inches (millimeters).  
 B. This drawing is subject to change without notice.  
 C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).  
 D. The package thermal performance may be enhanced by bonding the thermal pad to an external thermal plane. This pad is electrically and thermally connected to the backside of the die and possibly selected leads.

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